

Fast Switching Emitter Controlled Diode



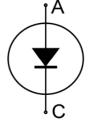


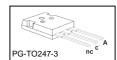




Features:

- 600V EmCon technology
- Fast recovery
- Soft switching
- Low reverse recovery charge
- Low forward voltage
- 175°C junction operating temperature
- Easy paralleling
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models: http://www.infineon.com/emcon/





Applications:

- Welding
- Motor drives

Туре	V_{RRM}	I F	V _{F,Tj=25°C}	$T_{j,max}$	Marking	Package
IDW75E60	600V	75 A	1.65V	175°C	D75E60	PG-TO247-3

Datasheet IDW75E60

Maximum Ratings

Parameter	Symbol	Value	Unit	
Repetitive peak reverse voltage	V_{RRM}	600	V	
Continuous forward current				
$T_{\rm C} = 25^{\circ}{\rm C}$	ı	120	_	
$T_{\rm C} = 90^{\circ}{\rm C}$	l _F	82	Α	
$T_{\rm C} = 100^{\circ}{\rm C}$		75		
Surge non repetitive forward current	ı	220	_	
$T_{\rm C}$ = 25°C, $t_{\rm p}$ = 10 ms, sine halfwave	I _{FSM}	220	A	
Maximum repetitive forward current	ı	225	Α	
$T_{\rm C} = 25^{\circ}$ C, $t_{\rm p}$ limited by $t_{\rm j,max}$, $D = 0.5$	I _{FRM}	225	^	
Power dissipation				
$T_{\rm C} = 25^{\circ}{\rm C}$	D	300	w	
$T_{\rm C} = 90^{\circ}{\rm C}$	P_{tot}	170	VV	
<i>T</i> _C = 100°C		150		
Operating junction temperature	T_{j}	-40+175		
Storage temperature	$T_{\rm stg}$	-55+150	°C	
Soldering temperature 1.6mm (0.063 in.) from case for 10 s	Ts	260		

Value

typ.

min.

Unit

max.



Thermal Resista

Parameter

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic	, ,			.
Thermal resistance,	R _{thJC}		0.5	K/W
junction – case				
Thermal resistance,	R_{thJA}		40	
junction – ambient				

Electrical Characteristic, at $T_j = 25$ °C, unless otherwise specified

Symbol

Static Characteristic						
Collector-emitter breakdown voltage	V_{RRM}	$I_R=0.25\mathrm{mA}$	600	-	-	V
Diode forward voltage	V _F	I _F =75A				-
		<i>T</i> _j =25°C	-	1.65	2.0	
		<i>T</i> _j =175°C	-	1.65	-	
Reverse leakage current	I_{R}	V _R =600V				μΑ
		<i>T</i> _j =25°C	-	-	40	
		T175°C	_	_	2500	

Conditions

Dynamic Electrical Characteristics

Diode reverse recovery time	t_{rr}	<i>T</i> _j =25°C	-	121	-	ns
Diode reverse recovery charge	Q _{rr}	V_{R} =400V, I_{F} =75A,	-	2.4	-	μC
Diode peak reverse recovery current	I _{rr}	$dI_F/dt=1460A/\mu s$	-	38.5	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI _{rr} /dt		-	921	-	A/µs

Diode reverse recovery time	t_{rr}	T _j =125°C	-	155	-	ns
Diode reverse recovery charge	Q_{rrm}	V_{R} =400V, I_{F} =75A,	-	4.4	-	μC
Diode peak reverse recovery current	I _{rr}	$dI_F/dt=1460A/\mu s$	-	46.6	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI _{rr} /dt		-	960	-	A/µs

Diode reverse recovery time	t_{rr}	<i>T</i> _j =175°C	-	182	-	ns
Diode reverse recovery charge	Q _{rrm}	V_{R} =400V, I_{F} =75A,	-	5.8	-	μC
Diode peak reverse recovery current	I _{rr}	$dI_F/dt=1460A/\mu s$	-	56.2	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI _{rr} /dt		-	1013	-	A/µs



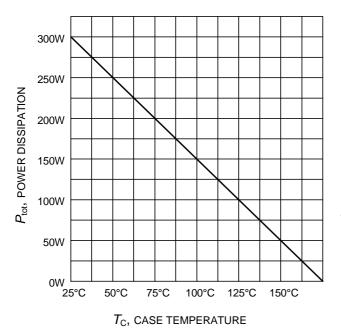
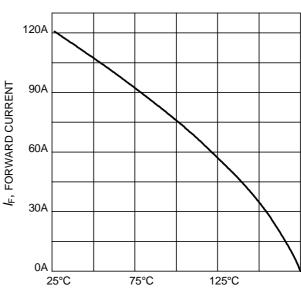


Figure 1. Power dissipation as a function of case temperature $(T_i \le 175^{\circ}\text{C})$



 $T_{\rm C}$, CASE TEMPERATURE Figure 2. Diode forward current as a function of case temperature $(T_{\rm i} \le 175^{\circ}{\rm C})$

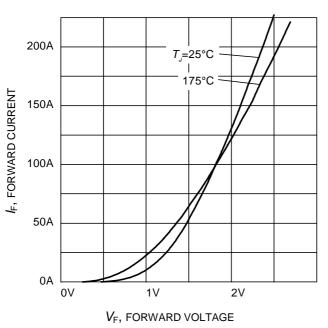
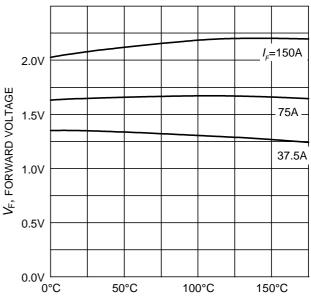


Figure 3. Typical diode forward current as a function of forward voltage



T_J, JUNCTION TEMPERATURE

Figure 4. Typical diode forward voltage as a function of junction temperature



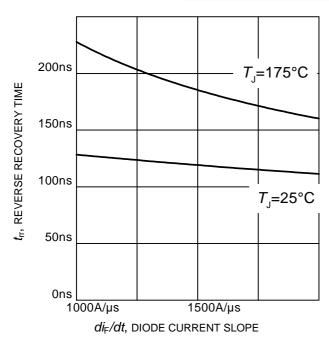
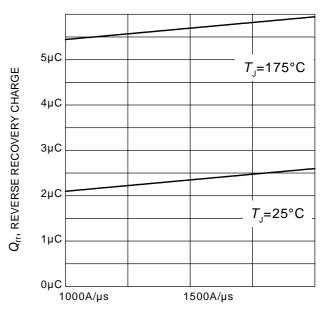


Figure 5. Typical reverse recovery time as a function of diode current slope (V_R =400V, I_F =75A, Dynamic test circuit in Figure E)



 $di_{\rm F}/dt$, DIODE CURRENT SLOPE Figure 6. Typical reverse recovery charge

as a function of diode current slope ($V_R = 400V$, $I_F = 75A$, Dynamic test circuit in Figure E)

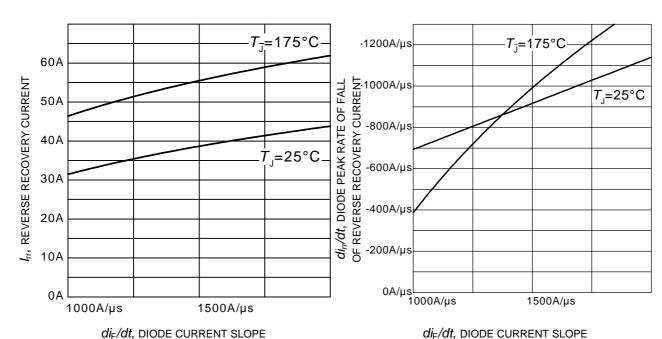


Figure 7. Typical reverse recovery current as a function of diode current slope $(V_R = 400 \text{V}, I_F = 75 \text{A},$

Dynamic test circuit in Figure E)

Figure 8. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope (V_R =400V, I_F =75A, Dynamic test circuit in Figure E)



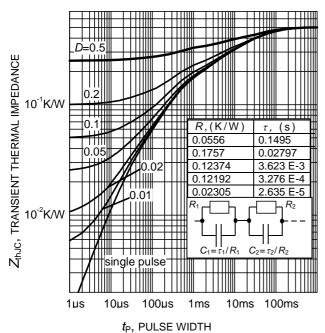
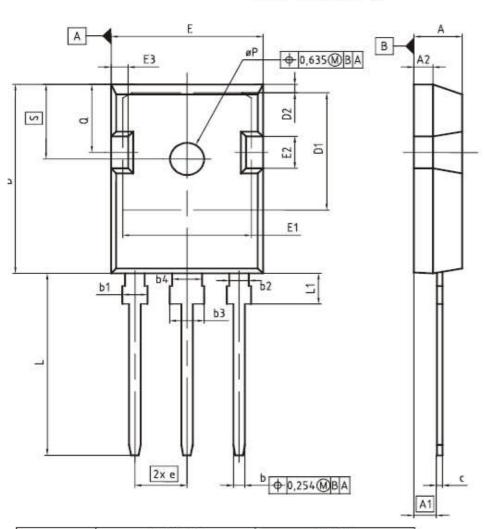


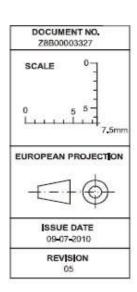
Figure 9. Diode transient thermal impedance as a function of pulse width $(D=t_{\rm P}/T)$



PG-TO247-3



DBM	MILLIM	ETERS	INCHES		
Dem	MIN	MAX	MIN	MAX	
A	4,83	5.21	0.190	0.205	
A1	2.27	2,54	0.089	0,100	
A2	1.85	2,16	0,073	0,085	
ь	1.07	1.33	0.042	0,052	
b1	1.90	2,41	0.075	0,095	
b2	1.90	2,16	0.075	0.085	
b3	2.87	3.38	0.113	0.133	
b4	2,87	3.13	0.113	0,123	
c	0.55	0.68	0.022	0.027	
D	20,80	21,10	0,819	0,831	
D1	16,25	17.65	0,640	0.695	
D2	0.95	1.35	0.037	0.053	
E	15.70	16,13	0.618	0,635	
E1	13.10	14.15	0,516	0,557	
E2	3.68	5.10	0.145	0,201	
E3	1,00	2.60	0.039	0,102	
e	5.	44 (BSC)	0.214 (BSC)		
N	8	3		3	
E	19,80	20,32	0.780	0.800	
Li	4.10	4.47	0.161	0.176	
øΡ	3,50	3.70	0.138	0,146	
Q	5,49	6,00	0.216	0,236	
S	6.04	6.30	0,238	0,248	





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